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TEST REPORT

Product : SOUND STORM Trade mark : SOUNDCANDY

Model/Type reference : SC3001

Serial Number : N/A

Report Number : EED32H000896 FCC ID : 2AFQL-SC3001 Date of Issue : Aug. 28, 2015

Test Standards : 47 CFR Part 15 Subpart C (2014)

Test result : PASS

Prepared for:

DUST STUDIO LTD 7/f, Flat B-03, Cheong Wah Factory Building, Tokwawan, Kowloon, HK

Prepared by:

Centre Testing International Group Co., Ltd. Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China

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Tested by:

Ware Xin

Reviewed by:

Eman-Li

1 [000

Date:

Aug. 28, 2015

Sheek Luo Lab supervisor

Check No.: 1022581390









2 Version

Version No.	Date	Description
00	Aug. 28, 2015	Original









































































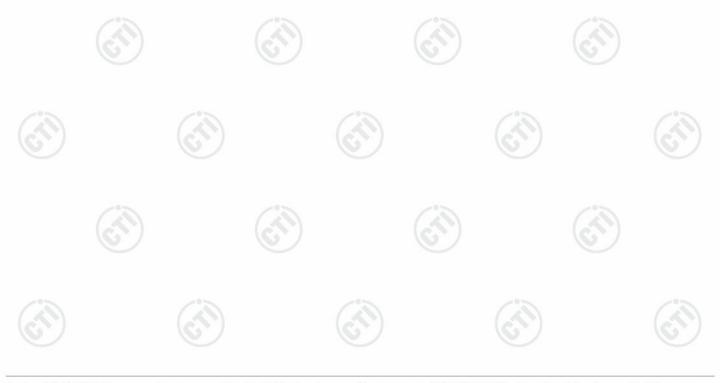


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3 Test Summary

rest Summary		(6.5)		
Test Item	Test Requirement	Test method	Result	
Antenna Requirement	47 CFR Part 15 Subpart C Section 15.203/15.247 (c)	ANSI C63.10-2013	PASS	
AC Power Line Conducted Emission	47 CFR Part 15 Subpart C Section 15.207	ANSI C63.10-2013	PASS	
Conducted Peak Output Power	47 CFR Part 15 Subpart C Section 15.247 (b)(1)	ANSI C63.10-2013	PASS	
20dB Occupied Bandwidth	47 CFR Part 15 Subpart C Section 15.247 (a)(1)	ANSI C63.10-2013	PASS	
Carrier Frequencies Separation	47 CFR Part 15 Subpart C Section 15.247 (a)(1)	ANSI C63.10-2013	PASS	
Hopping Channel Number	47 CFR Part 15 Subpart C Section 15.247 (b)	ANSI C63.10-2013	PASS	
Dwell Time	47 CFR Part 15 Subpart C Section 15.247 (a)(1)	ANSI C63.10-2013	PASS	
Pseudorandom Frequency Hopping Sequence	47 CFR Part 15 Subpart C Section 15.247(b)(4)&TCB Exclusion List (7 July 2002)	ANSI C63.10-2013	PASS	
RF Conducted Spurious Emissions	47 CFR Part 15 Subpart C Section 15.247(d)	ANSI C63.10-2013	PASS	
Radiated Spurious emissions	47 CFR Part 15 Subpart C Section 15.205/15.209	ANSI C63.10-2013	PASS	

Test according to ANSI C63.4-2014 & ANSI C63.10-2013.





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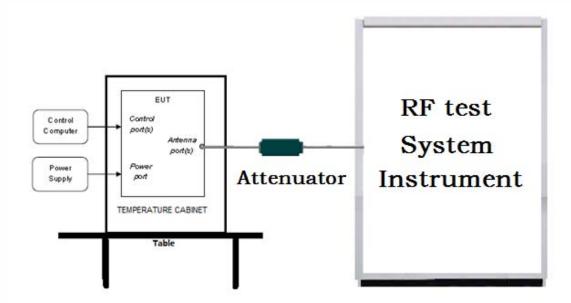


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5 Test Requirement

5.1 Test setup

5.1.1 For Conducted test setup



5.1.2 For Radiated Emissions test setup

Radiated Emissions setup:

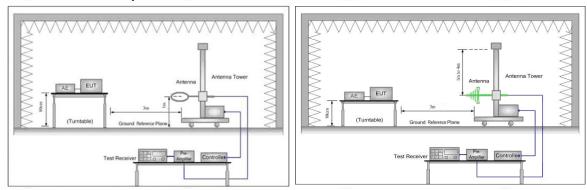


Figure 1. Below 30MHz

Figure 2. 30MHz to 1GHz

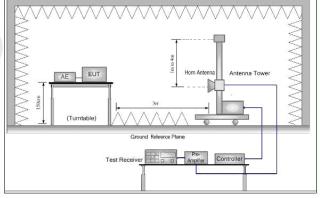
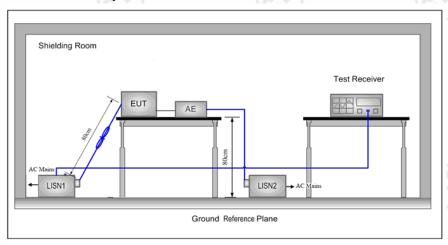


Figure 3. Above 1GHz



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5.1.3 For Conducted Emissions test setup Conducted Emissions setup

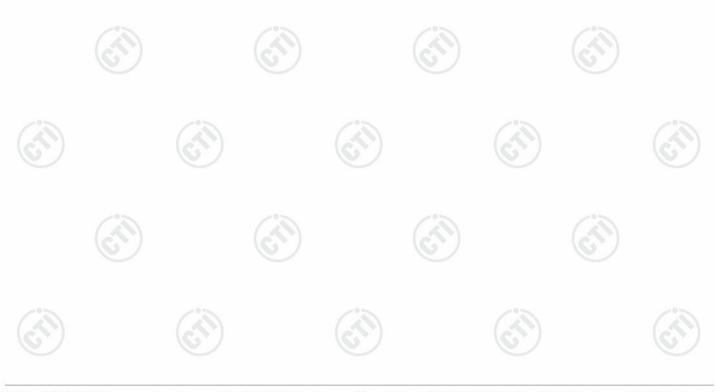


5.2 Test Environment

Operating Environment:		(6)
Temperature:	23 °C	
Humidity:	51 % RH	
Atmospheric Pressure:	1010mbar	

5.3 Test Condition

Test Mode	Tx/Rx	RF Channel			
rest wode	IX/KX	Low(L)	Middle(M)	High(H)	
GFSK/π/4DQPSK/	2402MHz ~2480 MHz	Channel 1	Channel 40	Channel79	
8DPSK(DH1,DH3,DH5)	2402NITZ ~2400 NITZ	2402MHz	2441MHz	2480MHz	





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6 General Information

6.1 Client Information

Applicant:	DUST STUDIO LTD
Address of Applicant:	7/f, Flat B-03, Cheong Wah Factory Building, Tokwawan, Kowloon, HK
Manufacturer:	DUST STUDIO LTD
Address of Manufacturer:	7/f, Flat B-03, Cheong Wah Factory Building, Tokwawan, Kowloon, HK
Factory:	RICHSO R&D CENTER RICHSO ELECTRONIC FTY HONG KONG GREASTAR
Address of Factory:	NO.61 Nan Ling Road, Nan An Industrial area Nan An Village, Feng Gang, Shenzhen, Guangdong, China

6.2 General Description of EUT

Product Name:	SOUND STORM			
Model No.(EUT):	SC3001			
Trade mark:	SOUNDCANDY	C°>	C *>	
Power Supply:	DC 3.7V	(2)	(2)	(0)
Sample Received Date:	Jun 30, 2015			
Sample tested Date:	Jun 30, 2015 to A	ug. 28, 2015		

6.3 Product Specification subjective to this standard

Operation Frequency:	2402MHz~2480MHz	
Bluetooth Version:	3.0+EDR	
Modulation Technique:	Frequency Hopping Spread Spectrum(FHSS)	
Modulation Type:	GFSK, π/4DQPSK, 8DPSK	
Number of Channel:	79	
Sample Type:	Portable production	
Antenna Type:	Integral	
Antenna Gain:	0dBi	
Test Voltage:	DC 3.7V	
10.3		1631

Operation Frequency each of channel

Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency
1	2402MHz	21	2422MHz	41	2442MHz	61	2462MHz
2	2403MHz	22	2423MHz	42	2443MHz	62	2463MHz
3	2404MHz	23	2424MHz	43	2444MHz	63	2464MHz
4	2405MHz	24	2425MHz	44	2445MHz	64	2465MHz
5	2406MHz	25	2426MHz	45	2446MHz	65	2466MHz
6	2407MHz	26	2427MHz	46	2447MHz	66	2467MHz
7	2408MHz	27	2428MHz	47	2448MHz	67	2468MHz
8	2409MHz	28	2429MHz	48	2449MHz	68	2469MHz
9	2410MHz	29	2430MHz	49	2450MHz	69	2470MHz
10	2411MHz	30	2431MHz	50	2451MHz	70	2471MHz



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1	1/07	2412MHz	31	2432MHz	51	2452MHz	71	2472MHz
1	2	2413MHz	32	2433MHz	52	2453MHz	72	2473MHz
1	3	2414MHz	33	2434MHz	53	2454MHz	73	2474MHz
1	4	2415MHz	34	2435MHz	54	2455MHz	74	2475MHz
1	5	2416MHz	35	2436MHz	55	2456MHz	75	2476MHz
1	6	2417MHz	36	2437MHz	56	2457MHz	76	2477MHz
1	7	2418MHz	37	2438MHz	57	2458MHz	77	2478MHz
1	8	2419MHz	38	2439MHz	58	2459MHz	78	2479MHz
1	9	2420MHz	39	2440MHz	59	2460MHz	79	2480MHz
2	0	2421MHz	40	2441MHz	60	2461MHz	(0,	/

6.4 Description of Support Units

The EUT has been tested with associated equipment below

Description	Manufacturer	Model No.	Data Cable	Certification	Supplied by
Notebook	HP	G3	N/A	FCC DOC	CTI
Mouse	L.Selectron	M004	Un-shielded 1.2m	FCC DOC	CTI

6.5 Test Location

All tests were performed at:

Centre Testing International Group Co., Ltd.

Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China518101

Telephone: +86 (0) 755 33683668 Fax:+86 (0) 755 33683385

No tests were sub-contracted.

6.6 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

CNAS-Lab Code: L1910

Centre Testing International Group Co., Ltd. has been assessed and proved to be in compliance with CNAS-CL01 Accreditation Criteria for Testing and Calibration Laboratories (identical to ISO/IEC 17025: 2005 General Requirements) for the Competence of Testing and Calibration Laboratories..

A2LA-Lab Cert. No. 3061.01

Centre Testing International Group Co., Ltd. EMC Laboratory has been accredited by A2LA for technical competence in the field of electrical testing, and proved to be in compliance with ISO/IEC 17025: 2005 General Requirements for the Competence of Testing and Calibration Laboratories and any additional program requirements in the identified field of testing.

FCC-Registration No.: 565659

Centre Testing International Group Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the FCC (Federal Communications Commission). The acceptance letter from the FCC is maintained in our files. Registration 565659.



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IC-Registration No.: 7408A

The 3m Alternate Test Site of Centre Testing International Group Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for the performance of radiated measurements with Registration No. 7408A.

IC-Registration No.: 7408B

The 10m Alternate Test Site of Centre Testing International Group Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for the performance of radiated measurements with Registration No. 7408B.

NEMKO-Aut. No.: ELA503

Centre Testing International Group Co., Ltd. has been assessed the quality assurance system, the testing facilities, qualifications and testing practices of the relevant parts of the organization. The quality assurance system of the Laboratory has been validated against ISO/IEC 17025 or equivalent. The laboratory also fulfils the conditions described in Nemko Document NLA-10.

VCCI

The Radiation 3 &10 meters site of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-4096.

Main Ports Conducted Interference Measurement of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: C-4563.

Telecommunication Ports Conducted Disturbance Measurement of

Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: T-2146.

The Radiation 3 meters site of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-758

6.7 Deviation from Standards

None.

6.8 Abnormalities from Standard Conditions

None.

6.9 Other Information Requested by the Customer

None.

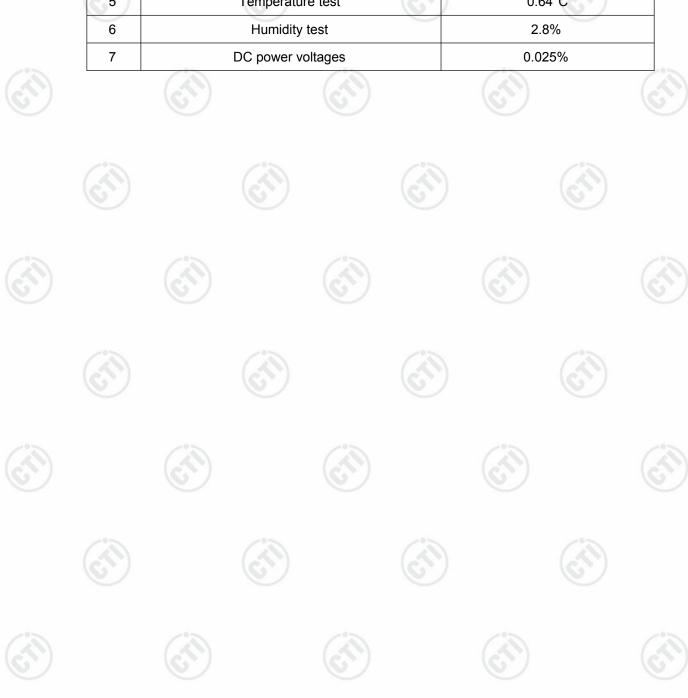




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6.10 Measurement Uncertainty (95% confidence levels, k=2)

Item	Measurement Uncertainty
Radio Frequency	7.9 x 10 ⁻⁸
DE novem conducted	0.31dB (30MHz-1GHz)
RF power, conducted	0.57dB (1GHz-18GHz)
Padiated Spurious amission tost	4.5dB (30MHz-1GHz)
Radiated Spurious emission test	4.8dB (1GHz-12.75GHz)
Conduction emission	3.6dB (9kHz to 150kHz)
Conduction emission	3.2dB (150kHz to 30MHz)
Temperature test	0.64°C
Humidity test	2.8%
DC power voltages	0.025%
	Radio Frequency RF power, conducted Radiated Spurious emission test Conduction emission Temperature test Humidity test

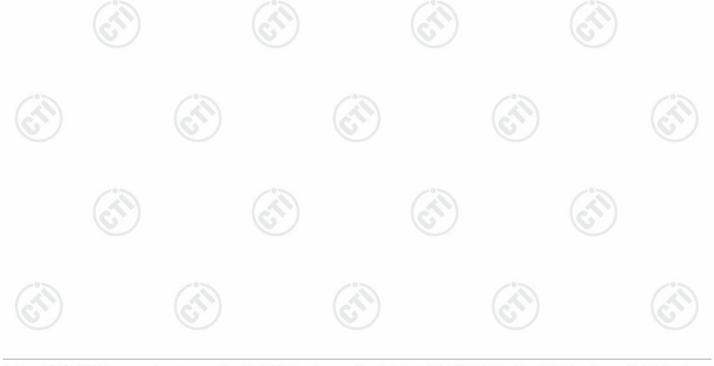




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7 Equipment List

		RF test s	system		
Equipment	Manufacturer	Mode No.	Serial Number	Cal. Date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)
Signal Generator	Keysight	E8257D	MY53401106	04-14-2015	04-13-2016
Communication test set test set	Agilent	N4010A	MY47230124	04-02-2015	04-01-2016
Spectrum Analyzer	Keysight	N9010A	MY54510339	04-01-2015	03-31-2016
Attenuator	HuaXiang	SHX370	15040701	04-01-2015	03-31-2016
Signal Generator	Keysight	N5182B	MY53051549	03-31-2015	03-30-2016
High-pass filter(3- 18GHz)	Sinoscite	FL3CX03WG18 NM12-0398-002		01-13-2015	01-12-2016
High-pass filter(5- 18GHz)	MICRO- TRONICS	SPA-F-63029-4		01-13-2015	01-12-2016
band rejection filter (GSM900)	Sinoscite	FL5CX01CA09C L12-0395-001		01-13-2015	01-12-2016
band rejection filter (GSM850)	Sinoscite	FL5CX01CA08C L12-0393-001		01-13-2015	01-12-2016
band rejection filter (GSM1800)	Sinoscite	FL5CX02CA04C L12-0396-002		01-13-2015	01-12-2016
band rejection filter (GSM1900)	Sinoscite	FL5CX02CA03C L12-0394-001	(2 1)	01-13-2015	01-12-2016
DC Power	Keysight	E3642A	MY54436035	03-31-2015	03-30-2016
PC-1	Lenovo	R4960d		04-01-2015	03-31-2016
BT&WI-FI Automatic control	R&S	OSPB157	101374	04-01-2015	03-31-2016
RF control unit	JS Tonscend	JS0806-2	2015860006	04-01-2015	03-31-2016
BT&WI-FI Automatic test software	JS Tonscend	JSTS1120-2		04-01-2015	03-31-2016





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Shielding Room No. 1 – Conduction Emission Test						
Equipment	Manufacturer	Mode No.	Serial Number	Cal. date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)	
Receiver	R&S	ESCI	100009	06-30-2014	06-28-2015	
Receiver	R&S	ESCI	100009	06-30-2015	06-28-2016	
LISN	R&S	ENV216	100098	11-12-2014	11-13-2015	

		3M Semi/full-anech	noic Chamber		
Equipment	Manufacturer	Mode No.	Serial Number	Cal. date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)
3M Chamber	TDK	SAC-3	(C)	06-02-2015	06-01-2016
TRILOG Broadband Antenna	schwarzbeck	VULB9163	9163-617	07-13-2014	07-12-2015
TRILOG Broadband Antenna	schwarzbeck	VULB9163	9163-617	07-13-2015	07-12-2016
Microwave Preamplifier	Agilent	8449B	3008A02425	02-05-2015	02-04-2016
Horn Antenna	ETS-LINDGREN	3117	00057410	06-30-2014	06-29-2015
Horn Antenna	ETS-LINDGREN	3117	00057410	06-30-2015	06-29-2016
Loop Antenna	ETS	6502	00071730	07-22-2014	07-21-2015
Loop Antenna	ETS	6502	00071730	07-22-2015	07-21-2016
Loop Antenna	ETS	6502	00071730	07-22-2014	07-21-2015
Loop Antenna	ETS	6502	00071730	07-22-2015	07-21-2016
Spectrum Analyzer	R&S	FSP40	100416	06-30-2014	06-29-2015
Spectrum Analyzer	R&S	FSP40	100416	06-30-2015	06-29-2016
Receiver	R&S	ESCI	100435	06-30-2014	06-29-2015
Receiver	R&S	ESCI	100435	06-30-2015	06-29-2016
Multi device Controller	maturo	NCD/070/10711112	(<u>4</u> 2)	01-13-2015	01-12-2016
LISN	schwarzbeck	NNBM8125	81251547	06-30-2014	06-29-2015
LISN	schwarzbeck	NNBM8125	81251547	06-30-2015	06-29-2016
LISN	schwarzbeck	NNBM8125	81251548	06-30-2014	06-29-2015
LISN	schwarzbeck	NNBM8125	81251548	06-30-2015	06-29-2016
Signal Generator	Agilent	E4438C	MY45095744	04-19-2015	04-18-2016
Signal Generator	Keysight	E8257D	MY53401106	04-14-2015	04-13-2016
Temperature/ Humidity Indicator	TAYLOR	1451	1905	07-09-2014	07-08-2015
Temperature/ Humidity Indicator	TAYLOR	1451	1905	07-09-2015	07-08-2016
Communication test set	Agilent	E5515C	GB47050533	01-13-2015	01-12-2016
Cable line	Fulai(7M)	SF106	5219/6A	01-13-2015	01-12-2016
Cable line	Fulai(6M)	SF106	5220/6A	01-13-2015	01-12-2016





Cable line	Fulai(3M)	SF106	5216/6A	01-13-2015	01-12-2016
Cable line	Fulai(3M)	SF106	5217/6A	01-13-2015	01-12-2016
Communication test set	R&S	CMW500	152394	04-19-2015	04-18-2016
High-pass filter(3- 18GHz)	Sinoscite	FL3CX03WG18NM 12-0398-002		01-13-2015	01-12-2016
High-pass filter(5- 18GHz)	MICRO- TRONICS	SPA-F-63029-4		01-13-2015	01-12-2016
band rejection filter	Sinoscite	FL5CX01CA09CL1 2-0395-001		01-13-2015	01-12-2016
band rejection filter	Sinoscite	FL5CX01CA08CL1 2-0393-001	<u></u>	01-13-2015	01-12-2016
band rejection filter	Sinoscite	FL5CX02CA04CL1 2-0396-002	(C,T.)	01-13-2015	01-12-2016
band rejection filter	Sinoscite	FL5CX02CA03CL1 2-0394-001		01-13-2015	01-12-2016









8 Radio Technical Requirements Specification

Reference documents for testing:

	No.	Identity	Document Title
	1	FCC Part15C (2014)	Subpart C-Intentional Radiators
1	2	ANSI C63.10-2013	American National Standard for Testing Unlicesed Wireless Devices

Test Results List:

COL INCOURS EIGH.				
Test requirement	Test method	Test item	Verdict	Note
Part15C Section 15.247 (a)(1)	ANSI 63.10	20dB Occupied Bandwidth	PASS	Appendix A)
Part15C Section 15.247 (a)(1)	ANSI 63.10	Carrier Frequencies Separation	PASS	Appendix B)
Part15C Section 15.247 (a)(1)	ANSI 63.10	Dwell Time	PASS	Appendix C)
Part15C Section 15.247 (b)	ANSI 63.10	Hopping Channel Number	PASS	Appendix D)
Part15C Section 15.247 (b)(1)	ANSI 63.10	Conducted Peak Output Power	PASS	Appendix E)
Part15C Section 15.247(d)	ANSI 63.10	Band-edge for RF Conducted Emissions	PASS	Appendix F)
Part15C Section 15.247(d)	ANSI 63.10	RF Conducted Spurious Emissions	PASS	Appendix G)
Part15C Section 15.247 (a)(1)	ANSI 63.10	Pseudorandom Frequency Hopping Sequence	PASS	Appendix H)
Part15C Section 15.203/15.247 (c)	ANSI 63.10	Antenna Requirement	PASS	Appendix I)
Part15C Section 15.207	ANSI 63.10	AC Power Line Conducted Emission	PASS	Appendix J)
Part15C Section 15.205/15.209	ANSI 63.10	Restricted bands around fundamental frequency (Radiated) Emission)	PASS	Appendix K)
Part15C Section 15.205/15.209	ANSI 63.10	Radiated Spurious Emissions	PASS	Appendix K)













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Appendix A) 20dB Occupied Bandwidth Test Result

Mode	Channel.	20dB Bandwidth [MHz]	99% OBW [MHz]	Verdict
GFSK	LCH	0.7518	0.80938	PASS
GFSK	MCH	0.7548	0.80877	PASS
GFSK	HCH	0.7552	0.81021	PASS
π/4DQPSK	LCH	1.150	1.0970	PASS
π/4DQPSK	МСН	1.151	1.0933	PASS
π/4DQPSK	нсн	1.152	1.0976	PASS
8DPSK	LCH	1.155	1.1057	PASS
8DPSK	МСН	1.153	1.1019	PASS
8DPSK	НСН	1.153	1.1048	PASS

Remark: Peak detector is used.

Test Graph





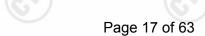


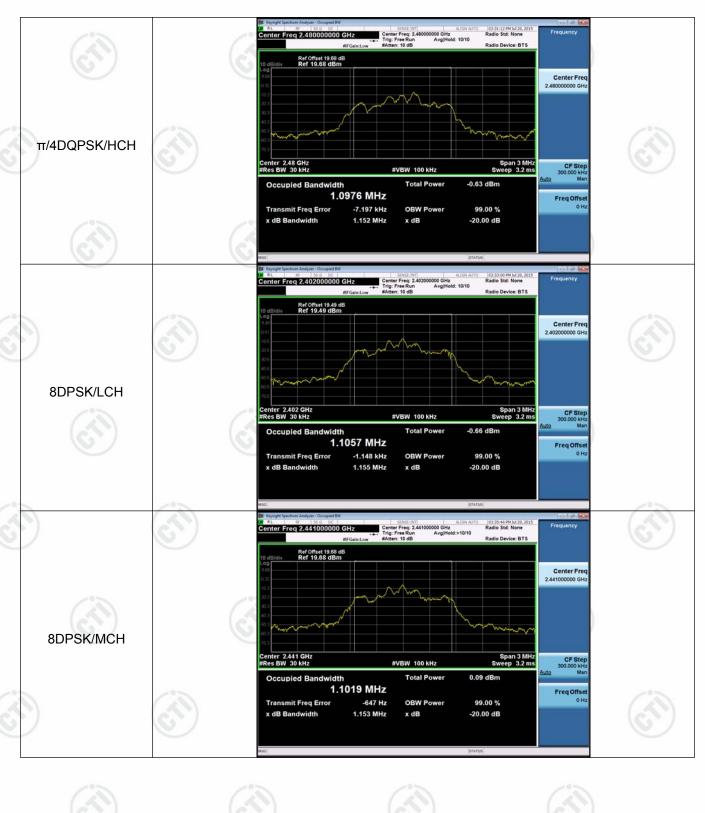




















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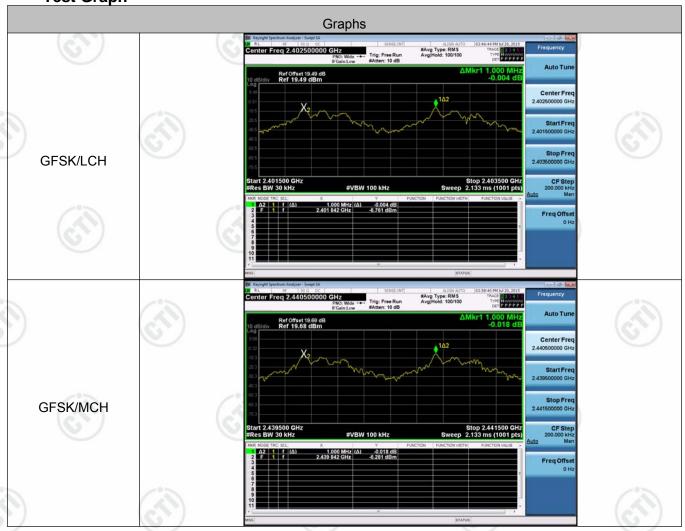


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Appendix B) Carrier Frequency Separation Result Table

Mode	Channel.	Carrier Frequency Separation [MHz]	Verdict
GFSK	LCH	1.000	PASS
GFSK	MCH	1.000	PASS
GFSK	HCH	1.000	PASS
π/4DQPSK	LCH	1.178	PASS
π/4DQPSK	MCH	0.924	PASS
π/4DQPSK	НСН	1.000	PASS
8DPSK	LCH	1.000	PASS
8DPSK	MCH	1.000	PASS
8DPSK	НСН	1.152	PASS

Test Graph













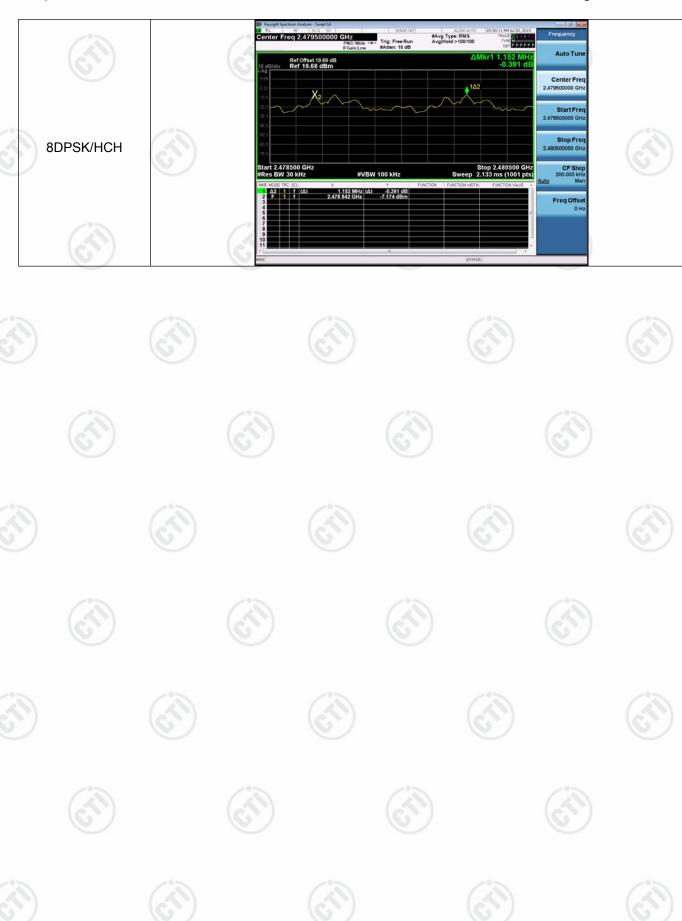














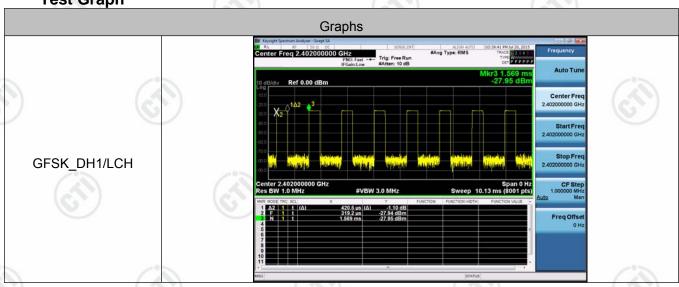
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Appendix C) Dwell Time Result Table

Mode	Packet	Channel	Burst Width [ms/hop/ch]	Total Hops[hop*ch]	Dwell Time[s]	Verdict
GFSK	DH1	LCH	0.421	320	0.135	PASS
GFSK	DH1	MCH	0.421	320	0.135	PASS
GFSK	DH1	НСН	0.419	320	0.134	PASS
GFSK	DH3	LCH	1.681	160	0.269	PASS
GFSK	DH3	MCH	1.681	160	0.269	PASS
GFSK	DH3	НСН	1.681	160	0.269	PASS
GFSK	DH5	LCH	2.93	106.7	0.313	PASS
GFSK	DH5	MCH	2.93	106.7	0.313	PASS
GFSK	DH5	нсн	2.93	106.7	0.313	PASS

Remark: Only worse case GFSK is reported.

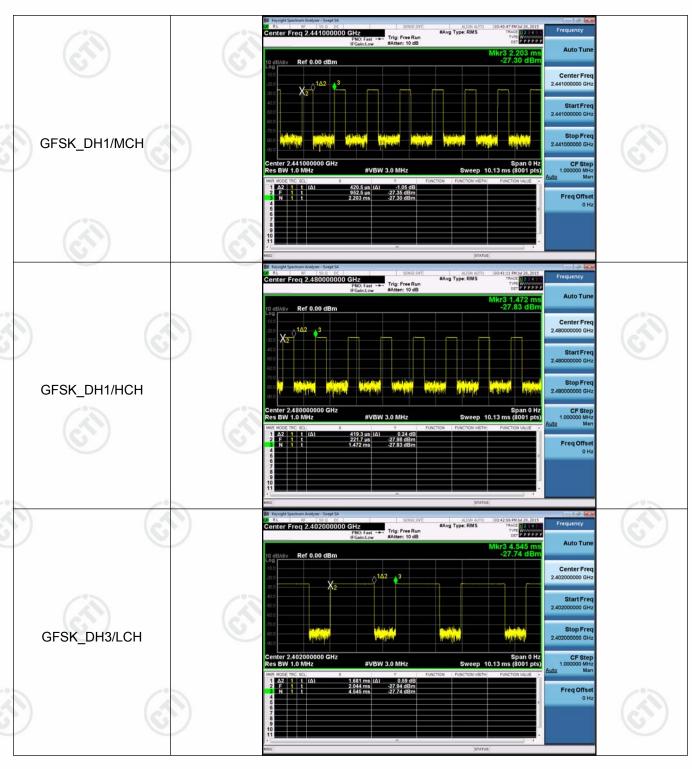
Test Graph







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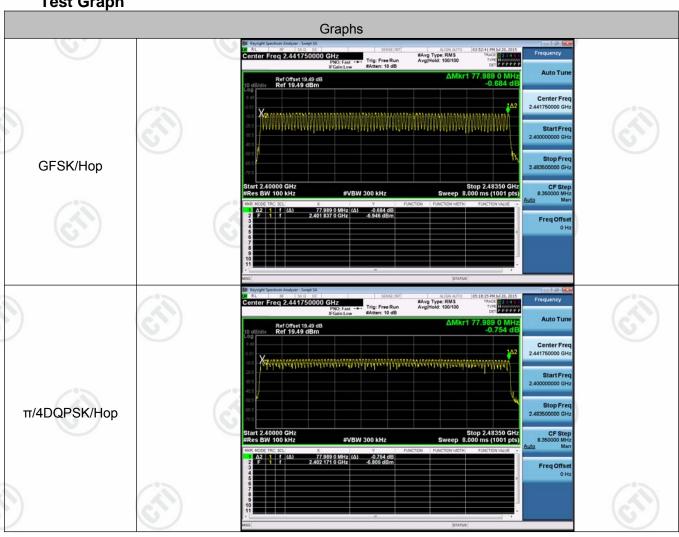


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Appendix D) Hopping Channel Number Result Table

Mode	Channel.	Number of Hopping Channel	Verdict
GFSK	Нор	79	PASS
π/4DQPSK	Нор	79	PASS
8DPSK	Нор	79	PASS

Test Graph



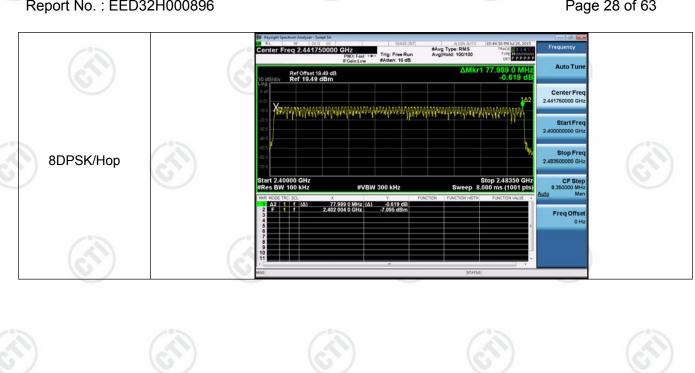




















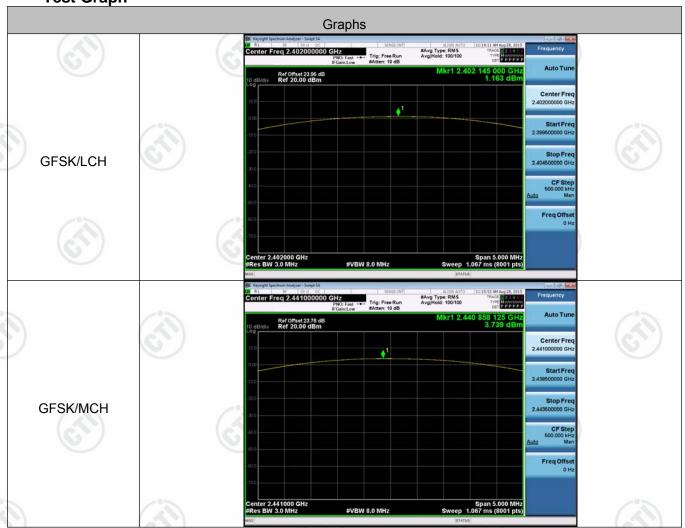




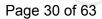
Appendix E) Conducted Peak Output Power Result Table

Mode	Channel.	Maximum Peak Output Power [dBm]	Verdict
GFSK	LCH	1.163	PASS
GFSK	MCH	3.739	PASS
GFSK	HCH	3.833	PASS
π/4DQPSK	LCH	0.411	PASS
π/4DQPSK	MCH	3.051	PASS
π/4DQPSK	HCH	3.185	PASS
8DPSK	LCH	1.024	PASS
8DPSK	MCH	3.531	PASS
8DPSK	нсн	3.636	PASS

Test Graph



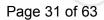


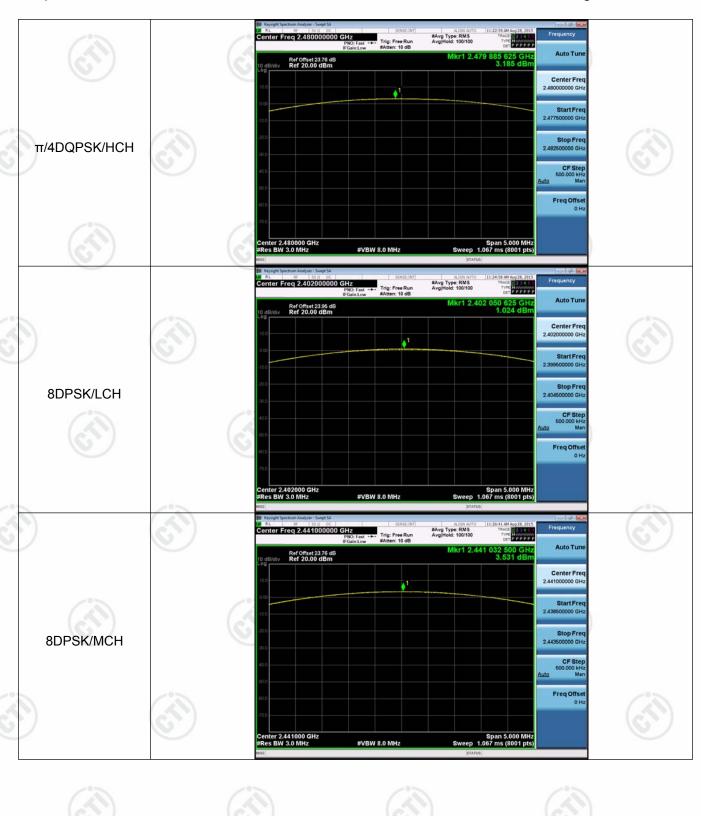


































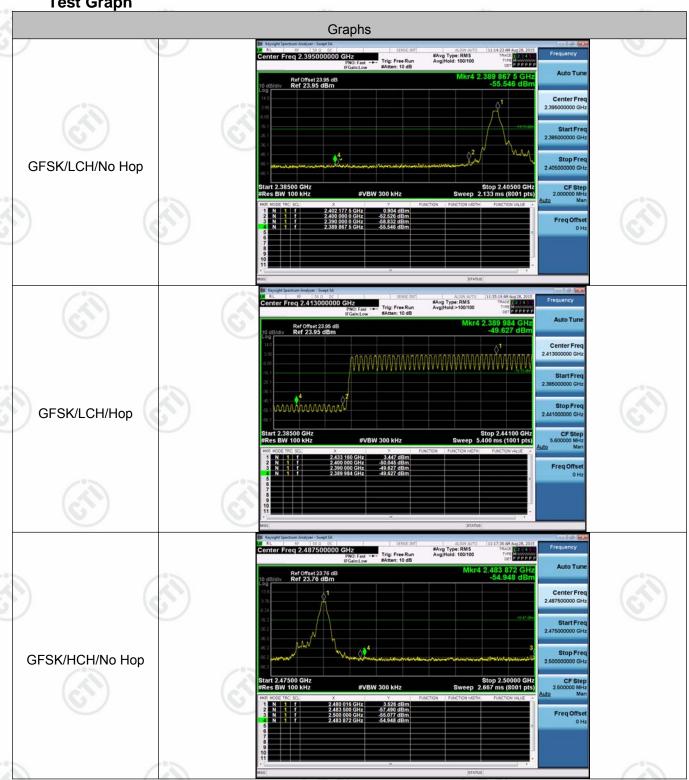




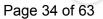
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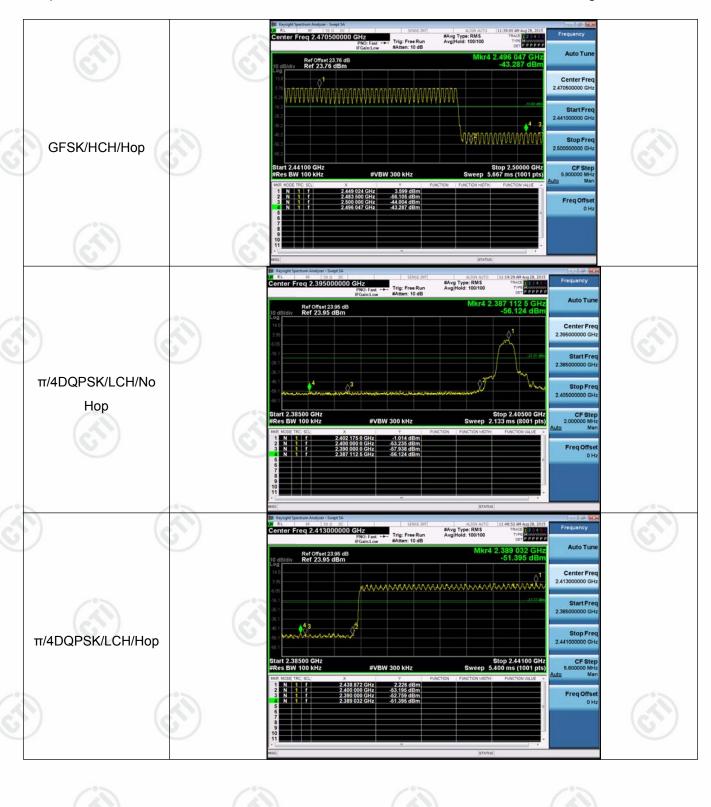
Appendix F) Band-edge for RF Conducted Emissions

Test Graph











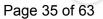


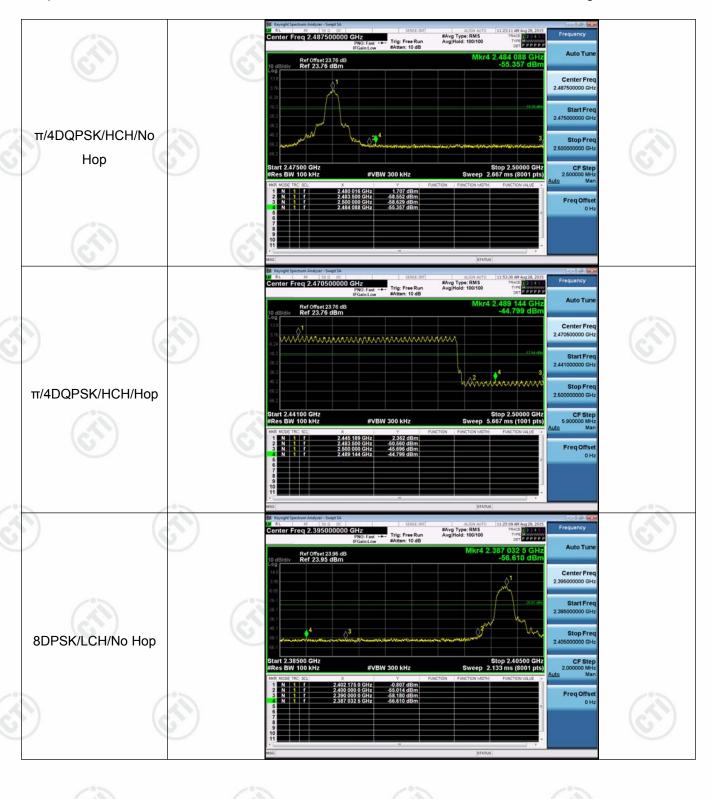
















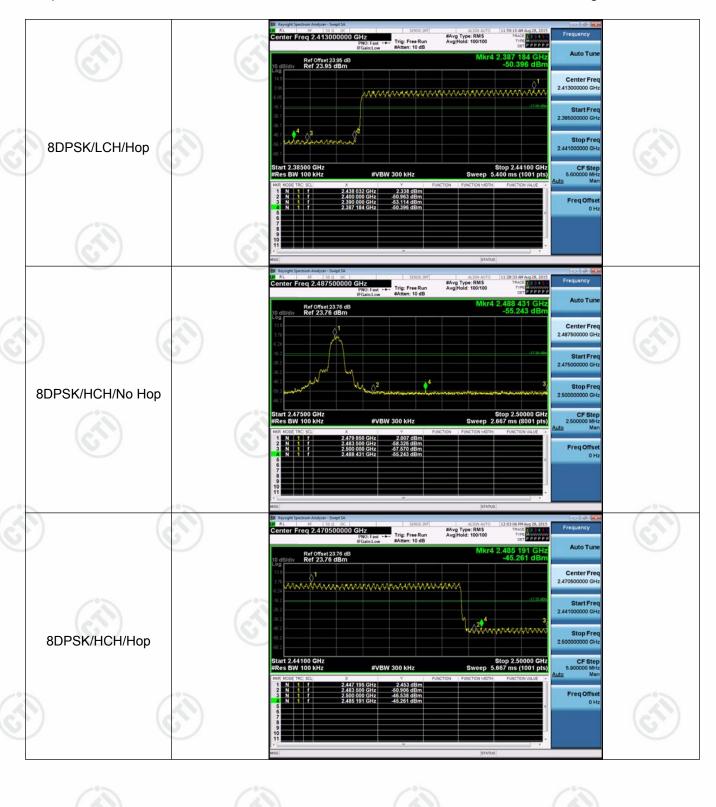








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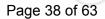
Appendix G) RF Conducted Spurious Emissions Result Table

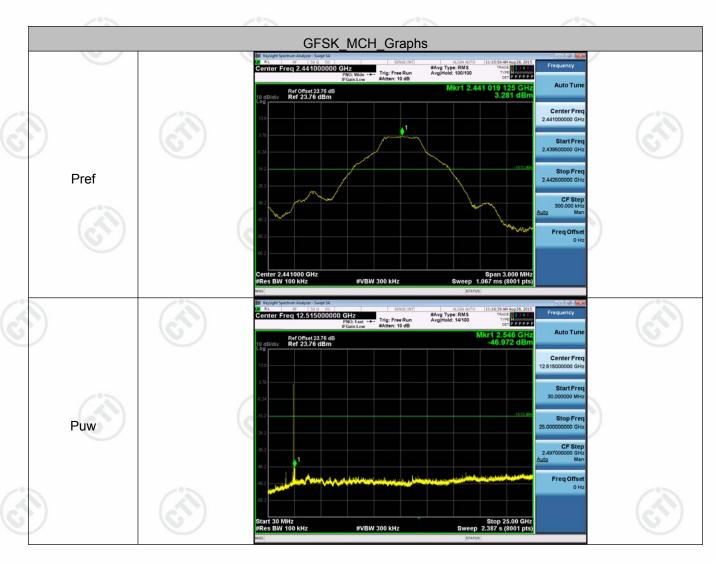
Test Graph

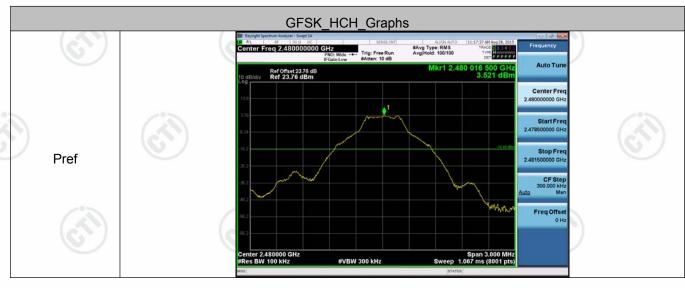


































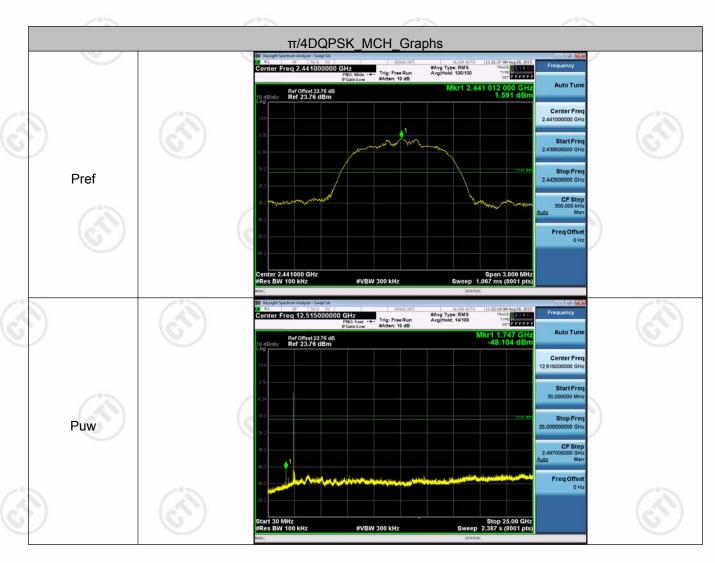


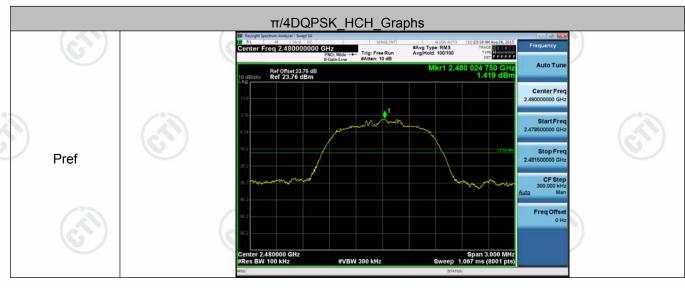


















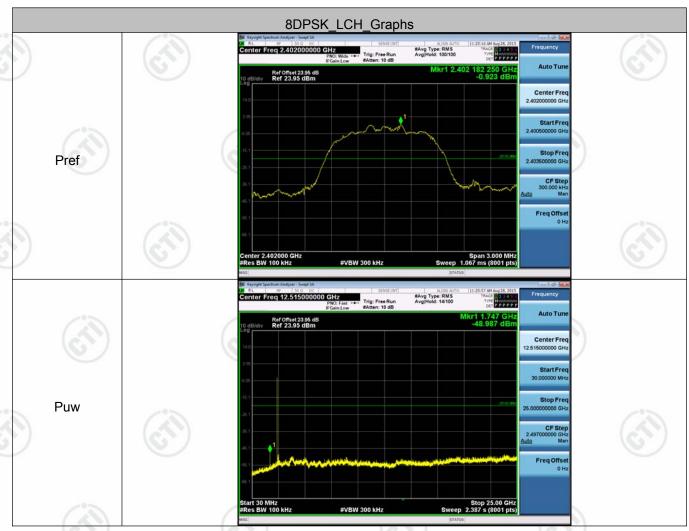
















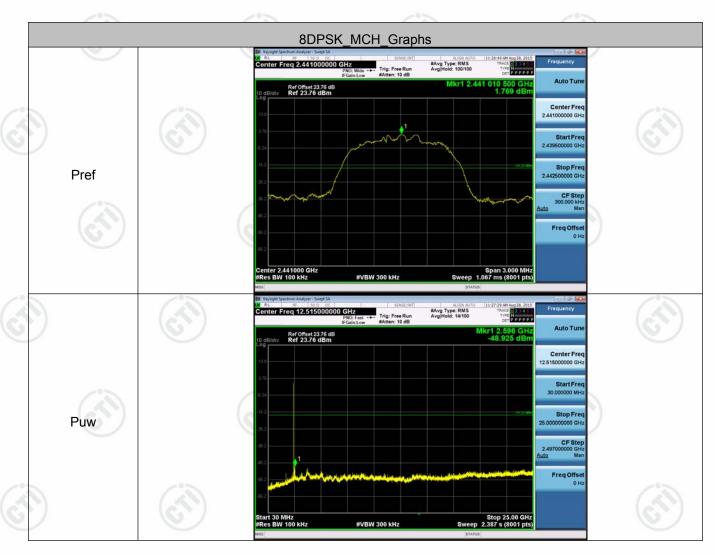


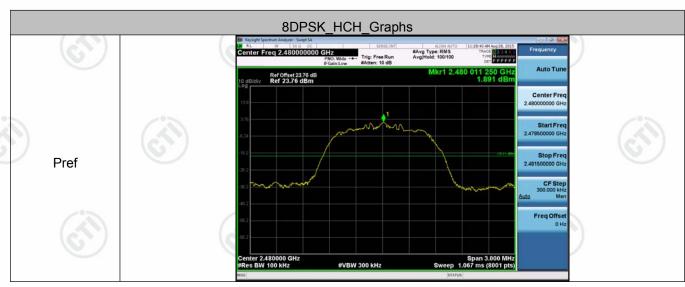




















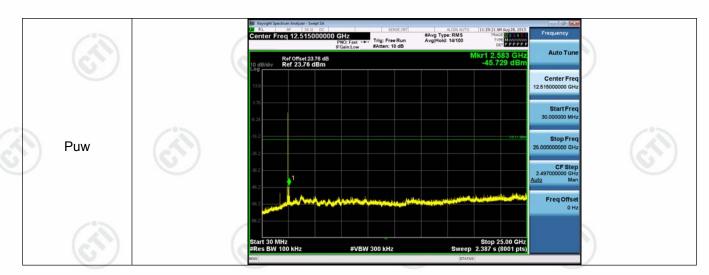








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Appendix H) Pseudorandom Frequency Hopping Sequence

Test Requirement:

47 CFR Part 15C Section 15.247 (a)(1) requirement:

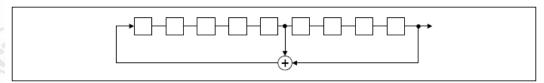
Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater.

Alternatively. Frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW. The system shall hop to channel frequencies that are selected at the system hopping rate from a Pseudorandom ordered list of hopping frequencies. Each frequency must be used equally on the average by each transmitter. The system receivers shall have input bandwidths that match the hopping channel bandwidths of their corresponding transmitters and shall shift frequencies in synchronization with the transmitted signals.

EUT Pseudorandom Frequency Hopping Sequence

The pseudorandom sequence may be generated in a nine-stage shift register whose 5th and 9th stage outputs are added in a modulo-two addition stage. And the result is fed back to the input of the first stage. The sequence begins with the first ONE of 9 consecutive ONEs; i.e. the shift register is initialized with nine ones.

- Number of shift register stages: 9
- Length of pseudo-random sequence: 29 -1 = 511 bits
- · Longest sequence of zeros: 8 (non-inverted signal)



Linear Feedback Shift Register for Generation of the PRBS sequence

An example of Pseudorandom Frequency Hopping Sequence as follow:

20 62 46 77 7 64 8 73 16 75 1

Each frequency used equally on the average by each transmitter.

The system receivers have input bandwidths that match the hopping channel bandwidths of their Corresponding transmitters and shift frequencies in synchronization with the transmitted signals.

The device does not have the ability to be coordinated with other FHSS systems in an effort to avoid the simultaneous occupancy of individual hopping frequencies by multiple transmitters.





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15.203 requirement:

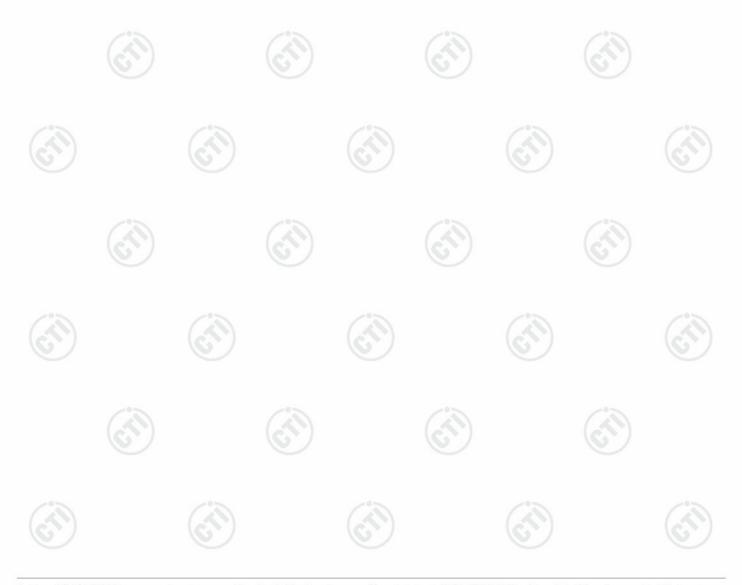
An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator, the manufacturer may design the unit so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited.

15.247(b) (4) requirement:

The conducted output power limit specified in paragraph (b) of this section is based on the use of antennas with directional gains that do not exceed 6 dBi. Except as shown in paragraph (c) of this section, if transmitting antennas of directional gain greater than 6 dBi are used, the conducted output power from the intentional radiator shall be reduced below the stated values in paragraphs (b)(1), (b)(2), and (b)(3) of this section, as appropriate, by the amount in dB that the directional gain of the antenna exceeds 6 dBi.

EUT Antenna:

The antenna is integrated on the main PCB and no consideration of replacement. The best case gain of the antenna is 0dBi.





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Appendix J) AC Power Line Conducted Emission

Test Procedure:	Test frequency range :150KHz 1)The mains terminal disturbar		nducted in a shiel	ded room.
	2) The EUT was connected to Stabilization Network) which power cables of all other under which was bonded to the graph for the unit being measured multiple power cables to a second connected to the	AC power source through provides a 50Ω/50μβ nits of the EUT were controlled reference plane in the countrilled to the countril	ugh a LISN 1 (Lin H + 5Ω linear imponnected to a se n the same way attet strip was use	ne Impedance bedance. The cond LISN as the LISN ed to conne
	exceeded. 3)The tabletop EUT was place reference plane. And for flo horizontal ground reference	or-standing arrangeme		•
	4) The test was performed with EUT shall be 0.4 m from the reference plane was bonded 1 was placed 0.8 m from the ground reference plane for the state of the sta	e vertical ground refere d to the horizontal grou he boundary of the un or LISNs mounted on	nce plane. The ve ind reference pla it under test and top of the grou	ertical grour ne. The LIS bonded to nd reference
	All other units of the EUT a LISN 2. 5) In order to find the maximum of the interface cables must	n emission, the relative	ent was at least 0 positions of equip	.8 m from the
	All other units of the EUT a LISN 2. 5) In order to find the maximum	nd associated equipment of associated equipment of a contraction of the relative	ent was at least 0 positions of equip	.8 m from the
_imit:	All other units of the EUT a LISN 2. 5) In order to find the maximum of the interface cables must	nd associated equipment of a continuity of the changed according	ent was at least 0 positions of equip to ANSI C63.10	.8 m from the
_imit:	All other units of the EUT a LISN 2. 5) In order to find the maximum of the interface cables must	nd associated equipment of associated equipment of a continuity of the changed according the changed according the change of the	ent was at least 0 positions of equip to ANSI C63.10	.8 m from the
Limit:	All other units of the EUT a LISN 2. 5) In order to find the maximum of the interface cables must conducted measurement.	nd associated equipment of a continuity of the changed according	ent was at least 0 positions of equip to ANSI C63.10	.8 m from the
_imit:	All other units of the EUT a LISN 2. 5) In order to find the maximum of the interface cables must conducted measurement. Frequency range (MHz)	nd associated equipment of associated equipment of a continuous co	positions of equip to ANSI C63.10 BµV) Average	.8 m from the
Limit:	All other units of the EUT at LISN 2. 5) In order to find the maximum of the interface cables must conducted measurement. Frequency range (MHz) 0.15-0.5	nd associated equipment of a emission, the relative be changed according Limit (dB Quasi-peak 66 to 56*	positions of equip to ANSI C63.10 BµV) Average 56 to 46*	.8 m from the





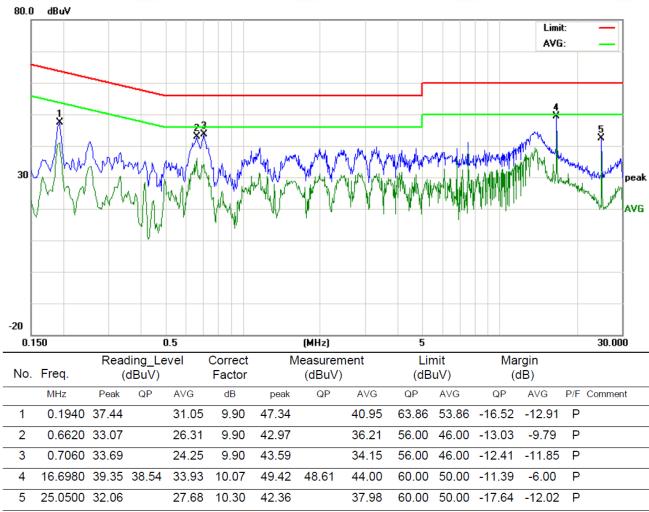
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Measurement Data

An initial pre-scan was performed on the live and neutral lines with peak detector.

Quasi-Peak and Average measurement were performed at the frequencies with maximized peak emission were detected.

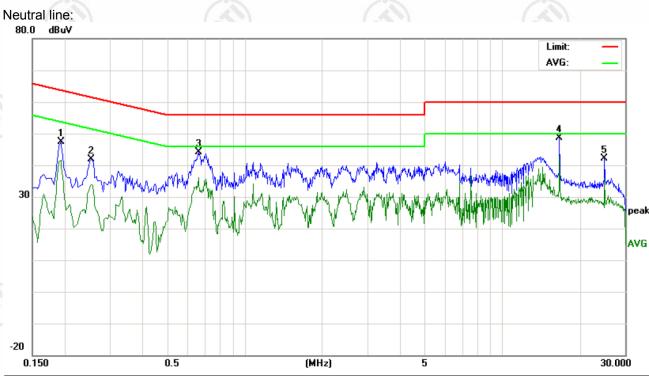
Live line:







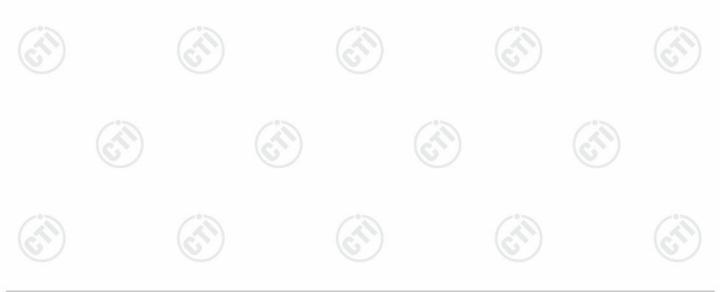




No.	Freq.		ding_Le	vel	Correct Factor	M	easurem (dBuV)	ent	Lin (dB			rgin dB)		
	MHz	Peak	QP	AVG	dB	peak	QP	AVG	QP	AVG	QP	AVG	P/F	Comment
1	0.1940	37.54		31.65	9.90	47.44		41.55	63.86	53.86	-16.42	-12.31	Р	
2	0.2540	32.00		24.00	9.90	41.90		33.90	61.62	51.62	-19.72	-17.72	Р	
3	0.6660	34.12		24.34	9.90	44.02		34.24	56.00	46.00	-11.98	-11.76	Р	
4	16.6980	38.55		32.90	10.07	48.62		42.97	60.00	50.00	-11.38	-7.03	Р	
5	25.0500	31.80		25.52	10.30	42.10		35.82	60.00	50.00	-17.90	-14.18	Р	

Notes:

- 1. The following Quasi-Peak and Average measurements were performed on the EUT:
- 2. Final Test Level =Receiver Reading + LISN Factor + Cable Loss.





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Appendix K) Restricted bands around fundamental frequency (Radiated)/Radiated Spurious Emissions

Receiver Setup:

Frequency	Detector	RBW	VBW	Remark
0.009MHz-0.090MHz	Peak	10kHz	30kHz	Peak
0.009MHz-0.090MHz	Average	10kHz	30kHz	Average
0.090MHz-0.110MHz	Quasi-peak	10kHz	30kHz	Quasi-peak
0.110MHz-0.490MHz	Peak	10kHz	30kHz	Peak
0.110MHz-0.490MHz	Average	10kHz	30kHz	Average
0.490MHz -30MHz	Quasi-peak	10kHz	30kHz	Quasi-peak
30MHz-1GHz	Quasi-peak	120 kHz	300kHz	Quasi-peak
Ab 4011-	Peak	1MHz	3MHz	Peak
Above 1GHz	Peak	1MHz	10Hz	Average

Test Procedure:

Below 1GHz test procedure as below:

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 meter semi-anechoic camber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, whichwas mounted on the top of a variable-height antenna tower.
- c. The antenna height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters (for the test frequency of below 30MHz, the antenna was tuned to heights 1 meter) and the rotatable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- f. If the emission level of the EUT in peak mode was 10dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10dB margin would be re-tested one by one using peak, quasi-peak or average method as specified and then reported in a data sheet.

Above 1GHz test procedure as below:

- g. Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber and change form table 0.8 meter to 1.5 meter(Above 18GHz the distance is 1 meter and table is 1.5 meter).
- h. Test the EUT in the lowest channel ,the middle channel ,the Highest channel
- i. The radiation measurements are performed in X, Y, Z axis positioning for Transmitting mode, and found the X axis positioning which it is worse case.
- Repeat above procedures until all frequencies measured was complete.







imit:	Frequency	equency Field strength Limit (microvolt/meter) (dBµV/m)		Remark	Measurement distance (m)	
	0.009MHz-0.490MHz	2400/F(kHz)	-	-	300	
	0.490MHz-1.705MHz	24000/F(kHz)	-	-	30	
	1.705MHz-30MHz	30	- ,	- Cin-	30	
	30MHz-88MHz	100	40.0	Quasi-peak	3	
	88MHz-216MHz	150	43.5	Quasi-peak	3	
	216MHz-960MHz	200	46.0	Quasi-peak	3	
	960MHz-1GHz	500	54.0	Quasi-peak	3	
	Above 1GHz	500	54.0	Average	3	
	Note: 15.35(b), Unless	otherwise specified	l, the limit or	n peak radio fr	equency	
	Note: 15.35(b), Unless emissions is 20dE applicable to the	16	l, the limit or um permitted st. This pea	n peak radio fr d average emi	equency ission limit	





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Radiated Spurious Emissions test Data:

All the modes of operation (X, Y, Z) were investigated and the worst-case emissions are reported.

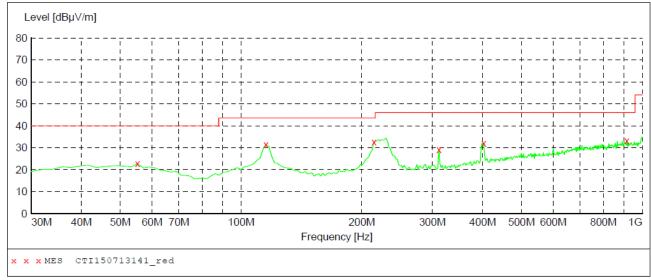
A. Below 30MHz:

No emissions were found higher than the background below 30MHz and background is lower than the limit, so it deems to compliance with the limit without recorded.

B. $30MHz \sim 1GHz$:

The test data of low channel, middle channel and high channel are almost same in frequency bands 30MHz to 1GHz, and the data of middle channel (GFSK mode) are chosen as worse case in below:

Remark: QP Detector is used.



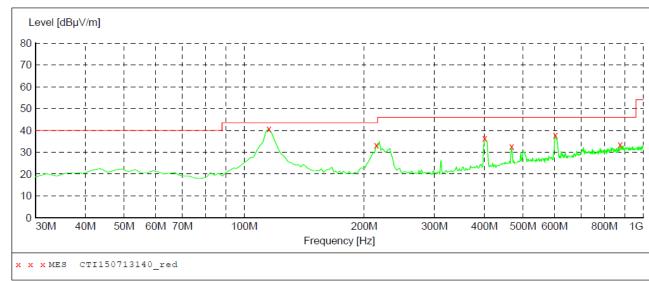
Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
55.220000 115.360000	22.70 31.40	15.8 13.5	40.0 43.5	17.3 12.1		200.0	170.00 262.00	HORIZONTAL HORIZONTAL
214.300000 311.300000	32.50 29.20	14.1 16.3	43.5 46.0	11.0 16.8		100.0 100.0	135.00 122.00	HORIZONTAL HORIZONTAL
402.480000 914.640000	32.00 33.10	19.2 26.7	46.0 46.0	14.0 12.9		100.0	29.00 370.00	HORIZONTAL HORIZONTAL





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Remark: QP Detector is used.



Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
115.360000	40.70	13.5	43.5	2.8		100.0	325.00	VERTICAL
214.300000	33.10	14.1	43.5	10.4		100.0	337.00	VERTICAL
400.540000	36.30	19.1	46.0	9.7		200.0	20.00	VERTICAL
468.440000	32.50	20.6	46.0	13.5		100.0	370.00	VERTICAL
602.300000	37.90	22.4	46.0	8.1		100.0	65.00	VERTICAL
875.840000	33.40	26.4	46.0	12.6		200.0	370.00	VERTICAL





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C. Above 1GHz:

Test Results-(Measurement Distance: 3m)_Channel low_2402MHz_GFSK mode:

Frequency (MHz)	•		Detector Type	Antenna (H/V)	Result (P/F)	
2390.0	37.82	74	PK	Н	Р	
2400.0	40.63	74	PK	Н	Р	
2402.0*	83.59		PK	Н	Р	
4804.0	46.16	74	PK	Н	Р	
2390.0	37.41	74	PK	V	Р	
2400.0	40.84	74	PK	V	Р	
2402.0*	85.13		PK	V	Р	
4804.0	47.55	74	PK	V	Р	

^{*:} fundamental frequency

Test Results-(Measurement Distance: 3m)_Channel middle_2441MHz_GFSK mode:

Frequency (MHz)	Measurement (dBuV/m)	Limit (dBuV/m)	Detector Type	Antenna (H/V)	Result (P/F)
2441.0*	86.09	N")	PK	н (с	Р
4882.0	44.39	74	PK	Н	Р
2441.0*	86.83		PK	V	Р
4882.0	47.85	74	PK	V	P

^{*:} fundamental frequency

Test Results-(Measurement Distance: 3m)_Channel high_2480MHz_GFSK mode:

Frequency (MHz)	Measurement (dBuV/m)	Limit (dBuV/m)	Detector Type	Antenna (H/V)	Result (P/F)
2480.0*	85.39	/	PK	н	Р
2483.5	43.83	74	PK	Н	Р
4960.0	46.42	74	PK	Н	Р
2480.0*	86.82	(241)	PK	V	Р
2483.5	43.75	74	PK	V	Р
4960.0	47.84	74	PK	V	Р

^{*:} fundamental frequency

Remark:

- 1. The above tables show that the frequencies peak data are all below the average limit, so the average data of these frequencies are deems to fulfill the average limits and not reported.
- 2. All the modes of GFSK, π /4-DQPSK and 8DPSK have been tested. The worst case is GFSK mode, and the worst data of GFSK mode are chosen as above.
- 3. No emission found from 18GHz to 25GHz.
- 4. All outside of operating frequency band and restricted band specified are below 15.209.



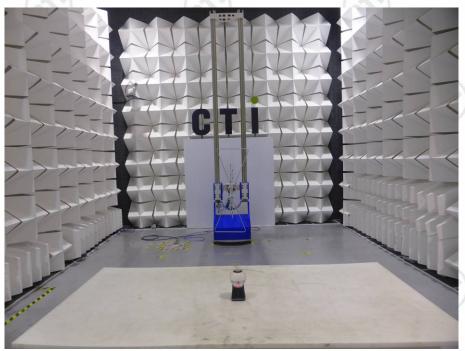
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Test mode No.: SC3001



Conducted Emission Test Setup

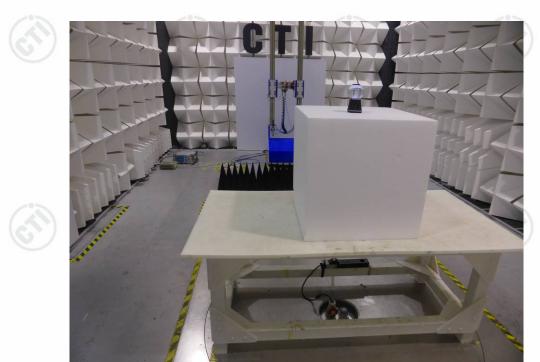


Radiated spurious emission Test Setup-1(Below 1GHz)









Radiated spurious emission Test Setup-2(Above 1GHz)

























































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PHOTOGRAPHS OF EUT Constructional Details



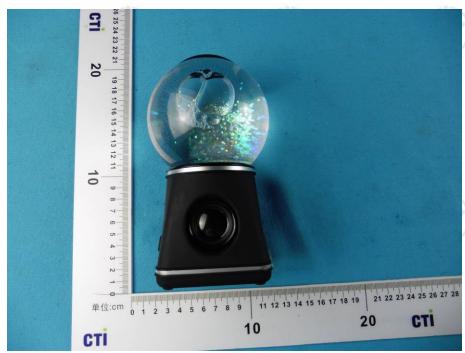
View of Product-1



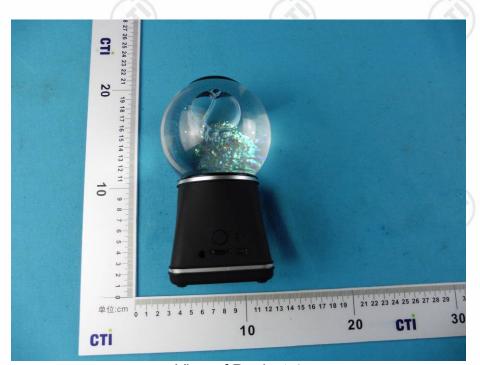








View of Product-3



View of Product-4





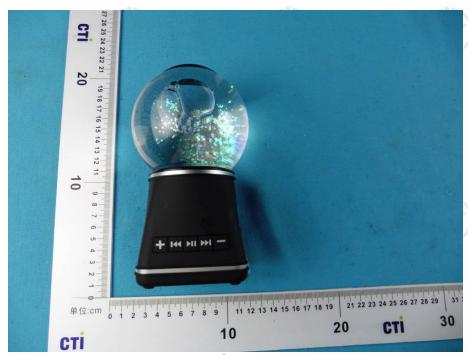




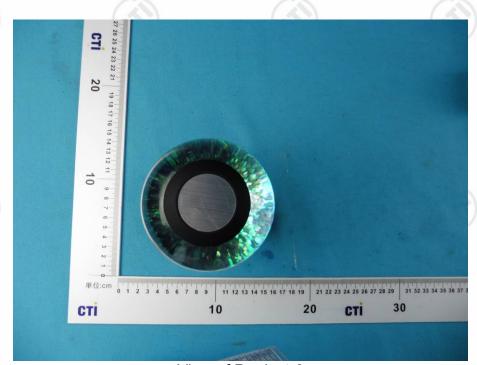








View of Product-5



View of Product-6



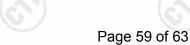






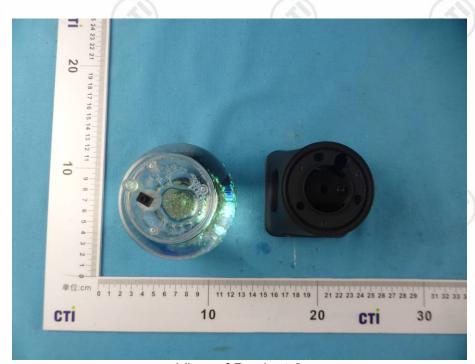








View of Product-7



View of Product-8





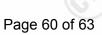


















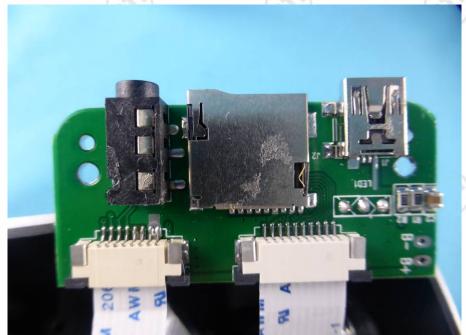
View of Product-9











View of Product-10













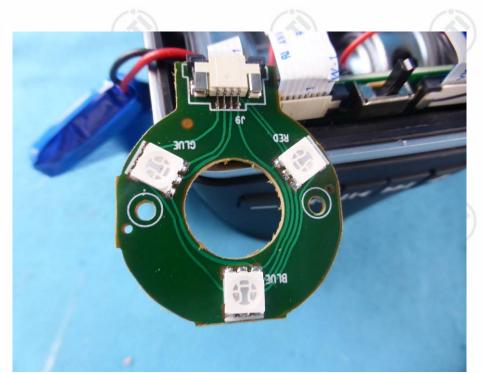








View of Product-11



View of Product-12











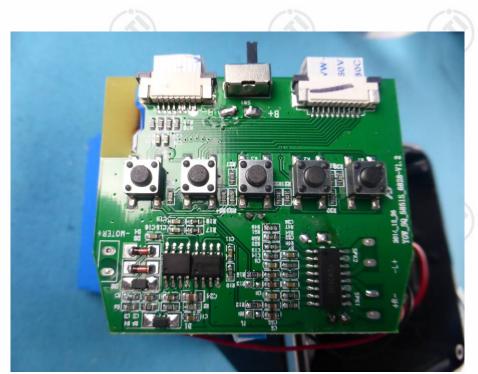








View of Product-13



View of Product-14





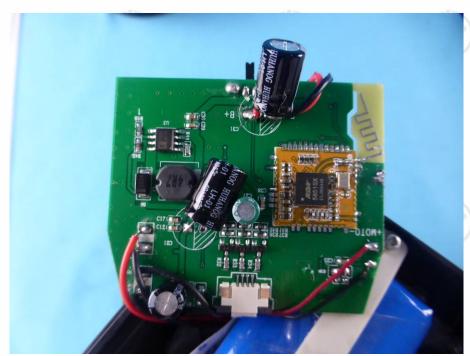








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View of Product-15



View of Product-16

*** End of Report ***

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